

Cascade

PA210 BlueRay

Fastest Production Testing Without Compromising Accuracy

Operation lamp for machine status

Instrument shelf for easy access to measurement equipment

Microscope

- High-resolution optics for probe inspection, wafer navigation and alignment

Universal platen setup

- For use with DC and RF positioners and probe cards

Base machine

- 200 mm x/y stage for reliable 24/7 operations
- Low maintenance
- Designed for fast die stepping up to 10 die/sec
- High-accuracy Z-stage for minimum scrub mark

Chuck

- Conductive chuck surface with vacuum holes for thin wafers
- Integrated AUX sites for calibration and cleaning sites
- Thermal test capability (25° C to 150° C)

Integrated vibration isolation system

- Eliminates vibration from external sources (acoustic, architectural, etc.)
- Enhances system stability
- Reduces damage to pads, wafers and probe tips

Small footprint machine table

- Integrates all prober components and supplies
- Integrated rollers

Electronics box

- Stable, industry standard machine controller
- Realtime PID motion controller
- Z-Profiling: Automatic wafer warpage compensation
- Integrated, reliable industrial PC for running Velox probe station control software

Velox™ probe station control software

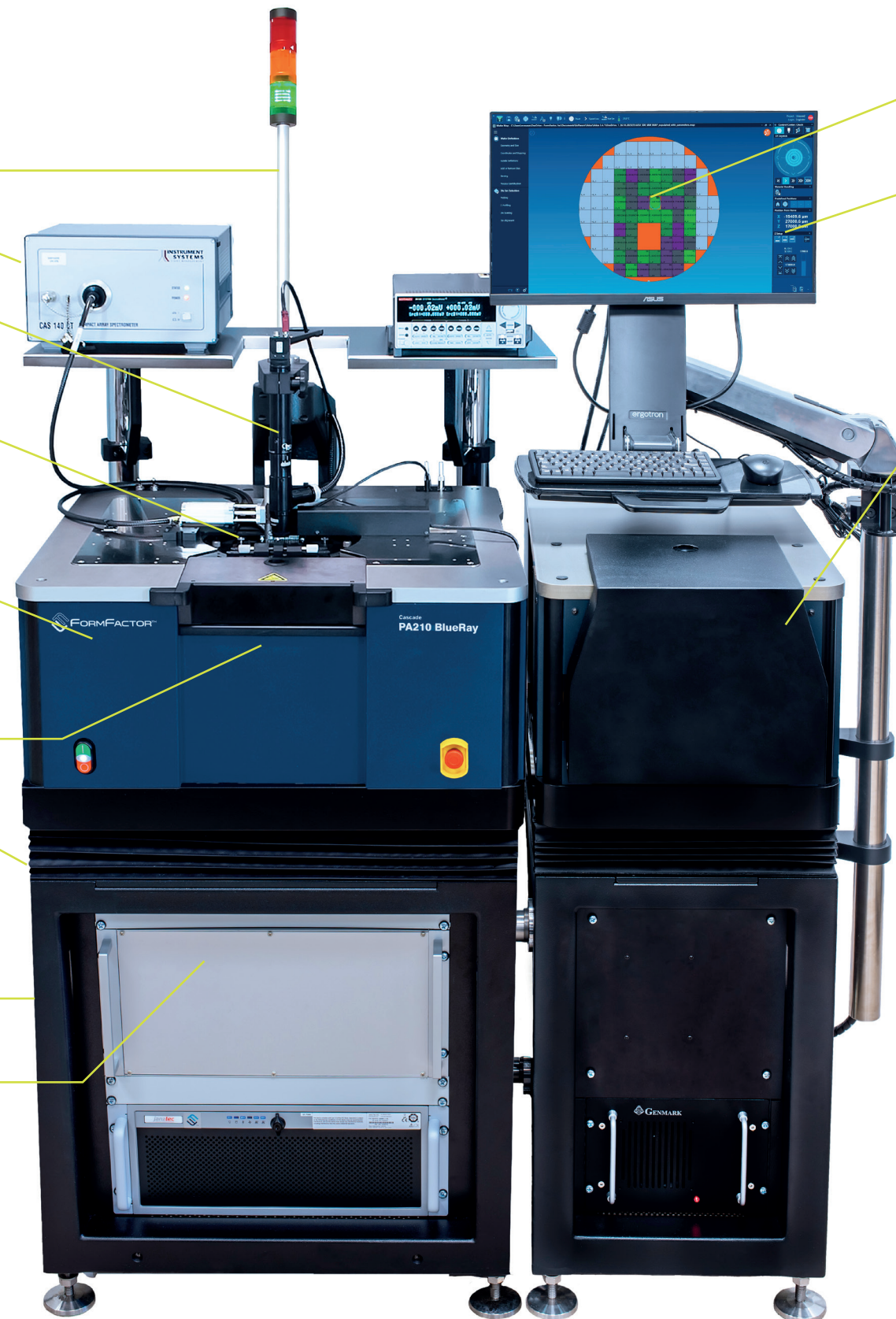
- Operate machine in a semi-automatic engineering mode
- Free die-to-die navigation on wafer
- Individual die testing

VeloxPro™ test automation software

- Easy-to-use SEMI E95 compliant user interface
- Efficient communication with test executive software
- Powerful pattern recognition capability

Loader module

- Universal cassette stand for substrates from 2" to 8"
- Integrated pre-aligner for flat/notch detection
- Barcode/2D matrix code/OCR wafer code recognition
- Field upgradeable



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